



PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Streamlined Precision Technologies, Inc. dba Advanced Measurement

**21 Bayview Terrace, Mill Valley, CA 94941
8900 Eton Ave., Suite F, Canoga Park, CA 91304**

*(Hereinafter called the Organization) and hereby declares that Organization is accredited
in accordance with the recognized International Standard:*

ISO/IEC 17025:2017

This accreditation demonstrates technical competence for a defined scope and the
operation of a laboratory quality management system
(as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

***Dimensional Calibration
(As detailed in the supplement)***

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this
certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the
Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen
President

Initial Accreditation Date:

January 20, 2017

Issue Date:

August 26, 2024

Expiration Date:

October 31, 2026

Accreditation No.:

93108

Certificate No.:

L24-653

Perry Johnson Laboratory
Accreditation, Inc. (PJLA)
755 W. Big Beaver, Suite 1325
Troy, Michigan 48084

*The validity of this certificate is maintained through ongoing assessments based on a
continuous accreditation cycle. The validity of this certificate should be
confirmed through the PJLA website: www.pjlab.com*



Certificate of Accreditation: Supplement

Streamlined Precision Technologies, Inc. dba Advanced Measurement

21 Bayview Terrace, Mill Valley, CA 94941

8900 Eton Ave, Canoga Park, CA 91304

Contact Name: Mr. Tom Gore Phone: 415-516-9760

Accreditation is granted to the facility to perform the following calibration:

Dimensional

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED	CALIBRATION MEASUREMENT METHOD OR PROCEDURES USED
CMM – Linear X, Y & Z Displacement ^{FO}	Up to 610 mm	$(1.8 + 3.3L) \mu\text{m}$	Step Gage	Procedure 200
CMM – Volumetric Accuracy ^{FO}	Up to 610 mm	$(1.8 + 3.3L) \mu\text{m}$	Step Gage / Sphere	
CMM – Repeatability ^{FO}	25.4 mm	$1.9 \mu\text{m}$	Sphere	
Optical Comparator – Squareness ^{FO}	Up to 300 mm	$(2.54 + 3.5L) \mu\text{m}$	Glass Scale/Grid Gage Blocks	Procedure 100 Procedure 300
Optical Comparator – Linearity X & Y ^{FO}	150 mm to 610 mm	$(2.54 + 3.5L) \mu\text{m}$		
Optical Comparator – Magnification ^{FO}	10X, 20X, 25X, 30X	0.02 % of Magnification		
	31.25X, 50X, 62.5X	0.04 % of Magnification		
Vision/Video Measurement Machine, Linearity X & Y ^{FO}	Up to 350 mm	$1.5 \mu\text{m}$	Glass Scale/Grid	PR B-001
	350 mm to 650 mm:	$2.2 \mu\text{m}$		
	650 mm to 850 mm	$2.4 \mu\text{m}$		
	850 mm to 2 540 mm	$(0.8 + 3.5L) \mu\text{m}$		
Vision/Video Measurement Machine, Linearity Z ^{FO}	Up to 100 mm:	$1.6 \mu\text{m}$	Gage Blocks	PR B-001
	100 mm to 200 mm	$1.7 \mu\text{m}$		
	200 mm to 300 mm	$1.8 \mu\text{m}$		
Calibration of 2-D and 1-D artefacts ^{FO}	Up to 300 mm steel	$3.5 \mu\text{m}$	Micro-Vu VMM	PR 7.2.1.1
	Up to 300 mm glass	$3.3 \mu\text{m}$		
Height Gage ^{FO}	Up to 500 mm	$(4.6 + 0.0005 L) \mu\text{m}$	Step Gage, Gage Blocks & Surface Plate	Procedure 400
Calipers ^{FO}		$(8.2 + 0.008 L) \mu\text{m}$		
Micrometers ^{FO}		$(1.6 + 0.005 L) \mu\text{m}$		
Indicators ^{FO}		$(1.0 + 0.003 L) \mu\text{m}$		

- The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.



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Accreditation is granted to the facility to perform the following calibration:

2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
3. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location.
4. The presence of a superscript O means that the laboratory performs calibration of the indicated parameter onsite at customer locations.
5. Measurement uncertainties obtained for calibrations performed at customer sites can be expected to be larger than the measurement uncertainties obtained at the laboratories fixed location for similar calibrations. This is due to the effects of transportation of the standards and equipment and upon environmental conditions at the customer site which are typically not controlled as closely as at the laboratories fixed location
6. The term L represents length in inches or millimeters as appropriate to the uncertainty statement.
7. The term "X" preceded by a number represents the number of times a lens system magnifies an image relative to its actual size. CMC stated as "% of magnification" represents the CMC of magnification expressed as a percentage of the total magnification.